



# UNIVERSITY OF SOUTH FLORIDA

## Single Source Certification

DATE:

Authority is requested to make the following purchase under the provision of USF System Regulation USF4.02010(IV)(A)(2)(b) as a non-competitive purchase available from only one source.

ITEM(S):

PRICE: \$

FUND #:

VENDOR ID:

REQUISITION#:

VENDOR NAME:

PURCHASE ORDER #:

FEDERAL GRANT:  Y  N

*Describe the equipment, commodity or contractual service and how it is to be used. Provide the justification for the single source (note price cannot be used for justification). Attach additional pages if necessary.*

This equipment is a unique system that combines three instruments in one, namely, conductive atomic force microscopy (cAFM), Kelvin force probe microscopy (KPFM) and tip-enhanced Raman spectroscopy (TERS). This is the only product on the market which can do tip-sample distance dependence indentation measurements with picometer scale control. This means that it is possible to change the distance between sample and scanning probe tip in a few tens of picometers steps with excellent stability. No other instrument can do that. Also this is the only system which is compatible for integration with the existing femtosecond laser in the Physics Department at USF.

  
Purchasing Agent

Date

Jeff Elliott  
Digitally signed by Jeff Elliott  
DN: cn=Jeff Elliott, o=University of South Florida, ou=Purchasing Services,  
email=jelliott13@usf.edu, c=US  
Date: 2018.05.16 08:20:01 -0400

Approved by:

Date

Authority: USF4.02010(IV)(A)(2)(b)

### PUBLIC POSTING

START DATE

END DATE

USF PURCHASING 18 MAY 17 09:59:23